Notice of References Cited	Application/Control No. Applicant(s)/P Reexamination OKAWA ET A		nt Under	
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	Sunil K. Singh	3732	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2005/0003323	01-2005	Katsuda et al.	433/029
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